# 4-Bit 24 Mb/s Dual-Supply Level Translator

The NLSX4378A is a 4-bit configurable dual-supply bidirectional auto sensing translator that does not require a directional control pin. The  $V_{CC}$  I/O and  $V_L$  I/O ports are designed to track two different power supply rails,  $V_{CC}$  and  $V_L$  respectively. The  $V_{CC}$  and  $V_L$  supply rails are configurable from 1.65 V to 5.5 V. This allows voltage logic signals on the  $V_L$  side to be translated into lower, higher or equal value voltage logic signals on the  $V_{CC}$  side, and vice-versa.

The NLSX4378A translator has open—drain outputs with integrated 10  $k\Omega$  pullup resistors on the I/O lines. The integrated pullup resistors are used to pullup the I/O lines to either  $V_L$  or  $V_{CC}$ . The NLSX4378A is an excellent match for open—drain applications such as the I²C communication bus.

#### **Features**

- V<sub>L</sub> can be Less than, Greater than or Equal to V<sub>CC</sub>
- Wide V<sub>CC</sub> Operating Range: 1.65 V to 5.5 V
   Wide V<sub>L</sub> Operating Range: 1.65 V to 5.5 V
- High-Speed with 24 Mb/s Guaranteed Date Rate
- Low Bit-to-Bit Skew
- Enable Input is Overvoltage Tolerant (OVT) to 5.5 V
- Nonpreferential Powerup Sequencing
- Integrated 10 kΩ Pullup Resistors
- ESD Protection: >7 kV HBM for all pins
- Small Space Saving Package 2.02 x 1.54 mm μBump12
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

# **Typical Applications**

- I<sup>2</sup>C, SMBus, PMBus
- Low Voltage ASIC Level Translation
- Mobile Phones, PDAs, Cameras



# ON Semiconductor®

www.onsemi.com



# μBump12 FC SUFFIX CASE 499AU

# MARKING DIAGRAM

O S4378AB AYWW

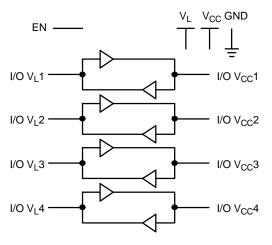
A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

#### **LOGIC DIAGRAM**



#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 8 of this data sheet.

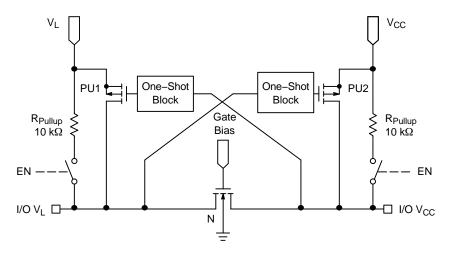


Figure 1. Block Diagram (1 I/O Line)

## **PIN ASSIGNMENT**

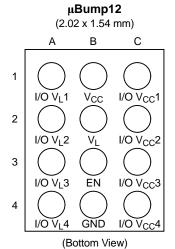
Pins	Description		
V <sub>CC</sub>	V <sub>CC</sub> Input Voltage		
V <sub>L</sub>	V <sub>L</sub> Input Voltage		
GND	Ground		
EN	Output Enable		
I/O V <sub>CC</sub> n	V <sub>CC</sub> I/O Port, Referenced to V <sub>CC</sub>		
I/O V <sub>L</sub> n	V <sub>L</sub> I/O Port, Referenced to V <sub>L</sub>		

## **FUNCTION TABLE**

EN	Operating Mode			
L	Hi–Z			
Н	I/O Buses Connected			

# **PIN LOCATION**

Pin	Pin Name
A1	I/O V <sub>L</sub> 1
A2	I/O V <sub>L</sub> 2
A3	I/O V <sub>L</sub> 3
A4	I/O VL4
B1	Vcc
B2	$V_{L}$
В3	EN
B4	GND
C1	I/O V <sub>CC</sub> 1
C2	I/O V <sub>CC</sub> 2
C3	I/O V <sub>CC</sub> 3
C4	I/O V <sub>CC</sub> 4



#### **MAXIMUM RATINGS**

Symbol	Parameter	Condition	Value	Unit
V <sub>CC</sub>	DC Supply Voltage		-0.3 to +7.0	V
V <sub>L</sub>	DC Supply Voltage		-0.3 to +7.0	V
I/O V <sub>CC</sub>	V <sub>CC</sub> -Referenced DC Input/Output Voltage		-0.3 to (V <sub>CC</sub> + 0.3)	V
I/O V <sub>L</sub>	V <sub>L</sub> -Referenced DC Input/Output Voltage		-0.3 to (V <sub>L</sub> + 0.3)	V
V <sub>EN</sub>	Enable Control Pin DC Input Voltage		-0.3 to +7.0	V
I <sub>I/O_SC</sub>	Short–Circuit Duration (I/O V <sub>L</sub> and I/O V <sub>CC</sub> to GND)	Continuous	40	mA
T <sub>STG</sub>	Storage Temperature		-65 to +150	°C
I <sub>LU</sub>	Latch-up Current		100	mA
ESD Rating	Human Body Model Charged Device Model		7000 2000	V

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	DC Supply Voltage	1.65	5.5	V
V <sub>L</sub>	DC Supply Voltage	1.65	5.5	V
V <sub>EN</sub>	Enable Control Pin Voltage	GND	5.5	V
V <sub>IO</sub>	I/O Pin Voltage	GND	V <sub>CC</sub> or V <sub>L</sub>	V
T <sub>A</sub>	Operating Temperature Range	-55	+125	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

# **DC ELECTRICAL CHARACTERISTICS** ( $V_{CC} = 1.65 \text{ V}$ to 5.5 V and $V_L = 1.65 \text{ V}$ to 5.5 V, unless otherwise specified)

			_	-40°C to +85°	C	−55°C to	+125°C	
Symbol	Parameter	Test Conditions	Min	Typ (Notes 1, 2)	Max	Min	Max	Unit
V <sub>IHC</sub>	I/O V <sub>CC</sub> Input HIGH Voltage		V <sub>CC</sub> - 0.4	-	-	V <sub>CC</sub> - 0.4	_	V
$V_{ILC}$	I/O V <sub>CC</sub> Input LOW Voltage		_	-	0.15	-	0.15	V
$V_{IHL}$	I/O V <sub>L</sub> Input HIGH Voltage		V <sub>L</sub> – 0.4	-	-	V <sub>L</sub> – 0.4	_	V
V <sub>ILL</sub>	I/O V <sub>L</sub> Input LOW Voltage		_	-	0.15	-	0.15	V
V <sub>IH</sub>	Control Pin Input HIGH Voltage		0.65 * V <sub>L</sub>	_	-	0.65 * V <sub>L</sub>	_	V
$V_{IL}$	Control Pin Input LOW Voltage		_	_	0.35 * V <sub>L</sub>	_	0.35 * V <sub>L</sub>	V
V <sub>OHC</sub>	I/O V <sub>CC</sub> Output HIGH Voltage	I/O V <sub>CC</sub> Source Current = 20 μA	0.8 * V <sub>CC</sub>	-	_	0.8 * V <sub>CC</sub>	-	V
V <sub>OLC</sub>	I/O V <sub>CC</sub> Output LOW Voltage	$I/O V_{CC}$ Sink Current = 1.0 mA, $I/O_{L} \le 0.15 V$	_	-	0.4	-	0.4	V
V <sub>OHL</sub>	I/O V <sub>L</sub> Output HIGH Voltage	I/O V <sub>L</sub> Source Current = 20 μA	0.8 * V <sub>L</sub>	_	-	0.8 * V <sub>L</sub>	-	V
V <sub>OLL</sub>	I/O V <sub>L</sub> Output LOW Voltage	I/O V <sub>L</sub> Sink Current = $1.0 \text{ mA}$ , I/O_V <sub>CC</sub> $\leq 0.15 \text{ V}$	-	-	0.4	_	0.4	V
I <sub>QVCC</sub>	V <sub>CC</sub> Supply Current	I/O V <sub>CC</sub> and I/O V <sub>L</sub> Unconnected, V <sub>EN</sub> = V <sub>L</sub>	-	0.5	2.0	_	3.0	μΑ
$I_{QVL}$	V <sub>L</sub> Supply Current	I/O V <sub>CC</sub> and I/O V <sub>L</sub> Unconnected, V <sub>EN</sub> = V <sub>L</sub>	_	0.3	1.0	_	3.0	μΑ
I <sub>TS-VCC</sub>	V <sub>CC</sub> Tristate Output Mode Supply Current	$I/O V_{CC}$ and $I/O V_{L}$ Unconnected, $V_{EN} = GND$	-	0.1	1.0	_	1.5	μΑ
I <sub>TS-VL</sub>	V <sub>L</sub> Tristate Output Mode Supply Current	$I/O V_{CC}$ and $I/O V_{L}$ Unconnected, $V_{EN} = GND$	_	0.1	1.0	_	1.5	μΑ
I <sub>OZ</sub>	I/O Tristate Output Mode Leakage Current	T <sub>A</sub> = +25°C	_	0.1	1.0	_	1.0	μΑ
R <sub>PU</sub>	Pullup Resistor I/O V <sub>L</sub> and V <sub>CC</sub>	T <sub>A</sub> = +25°C	_	10	_	_	-	kΩ

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics for the listed test conditions, unless other performance may not be indicated by the Electrical Characteristics if operated under different conditions.

1. Typical values are for  $V_{CC} = +2.8 \text{ V}$ ,  $V_L = +1.8 \text{ V}$  and  $T_A = +25^{\circ}\text{C}$ .

2. All units are production tested at  $T_A = +25^{\circ}\text{C}$ . Limits over the operating temperature range are guaranteed by design.

# TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS

(I/O test circuit of Figures 2 and 3,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

			-40°C to +85°C (Note 3)			-55°C to +125°C (Note 3)		
Symbol	Parameter	Test Conditions	Min	Тур	Max	Min	Max	Unit
V <sub>L</sub> = 1.65 V,	V <sub>CC</sub> = 5.5 V	<u> </u>			•	•		
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				15		15	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				30		30	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				30		30	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				10		10	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				20		20	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				20		20	ns
t <sub>SKEW</sub>	Channel-to-Channel Skew				5		5	nS
MDR	Maximum Data Rate		24			24		Mb/s
V <sub>L</sub> = 1.8 V, \	/ <sub>CC</sub> = 2.8 V				ı	ı	1	1
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				15		15	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				15		15	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				25		25	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				10		10	ns
t <sub>PDVL</sub> -VCC	Propagation Delay (Driving I/O V <sub>L</sub> )				15		15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				15		15	ns
t <sub>SKEW</sub>	Channel-to-Channel Skew				5		5	nS
MDR	Maximum Data Rate		24			24		Mb/s
V <sub>L</sub> = 2.5 V, \	/ <sub>CC</sub> = 3.6 V				- I	1	I	
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				15		15	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				10		10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				15		15	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				10		10	ns
t <sub>PDVL</sub> -VCC	Propagation Delay (Driving I/O V <sub>L</sub> )				15		15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				15		15	ns
t <sub>SKEW</sub>	Channel-to-Channel Skew				5		5	nS
MDR	Maximum Data Rate		24			24		Mb/s
V <sub>L</sub> = 2.8 V, \	/ <sub>CC</sub> = 1.8 V		<u> </u>		<u>.</u>			4
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				25		25	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				10		10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				15		15	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				15		15	ns
t <sub>PDVL</sub> -VCC	Propagation Delay (Driving I/O V <sub>L</sub> )				15		15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				15		15	ns
t <sub>SKEW</sub>	Channel-to-Channel Skew				5		5	nS
MDR	Maximum Data Rate		24			24		Mb/s

<sup>3.</sup> Limits over the operating temperature range are guaranteed by design.

# TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS

(I/O test circuit of Figures 2 and 3,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

			-40	0°C to +85 (Note 3)	5°C		<b>+125°C</b> te 3)	
Symbol	Parameter	Test Conditions	Min	Тур	Max	Min	Max	Unit
V <sub>L</sub> = 3.6 V, \	/ <sub>CC</sub> = 2.5 V							
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				15		15	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				10		10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				15		15	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				10		10	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				15		15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				15		15	ns
t <sub>SKEW</sub>	Channel-to-Channel Skew				5		5	nS
MDR	Maximum Data Rate		24			24		Mb/s
V <sub>L</sub> = 5.5 V, \	/ <sub>CC</sub> = 1.65 V							
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				30		30	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				10		10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				15		15	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				30		30	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				20		20	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				20		20	ns
t <sub>SKEW</sub>	Channel-to-Channel Skew				5		5	nS
MDR	Maximum Data Rate		24			24		Mb/s

<sup>3.</sup> Limits over the operating temperature range are guaranteed by design.

# TIMING CHARACTERISTICS - OPEN DRAIN DRIVING CONFIGURATIONS

(I/O test circuit of Figures 4 and 5,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

			-40°C to +85°C   -55 (Note 4)		<b>-55°C to +125°C</b> (Note 4)			
Symbol	Parameter	Test Conditions	Min	Тур	Max	Min	Max	Unit
+1.65 ≤ V <sub>L</sub> ,	$V_{CC} \leq +5.5 V$							
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				400		400	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				50		50	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				400		400	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				60		60	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				1000		1000	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				1000		1000	ns
t <sub>SKEW</sub>	Channel-to-Channel Skew				50		50	nS
MDR	Maximum Data Rate		2			2		Mb/s

<sup>4.</sup> Limits over the operating temperature range are guaranteed by design.

## **TEST SETUPS**

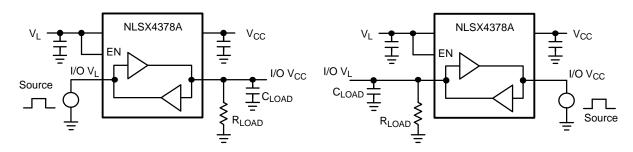


Figure 2. Rail-to-Rail Driving I/O V<sub>L</sub>

Figure 3. Rail-to-Rail Driving I/O V<sub>CC</sub>

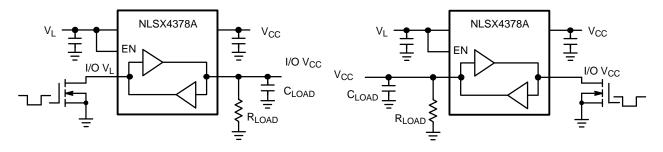


Figure 4. Open-Drain Driving I/O V<sub>L</sub>

Figure 5. Open-Drain Driving I/O V<sub>CC</sub>

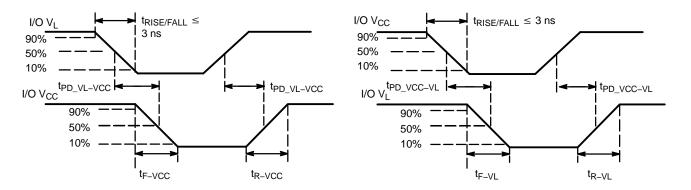


Figure 6. Definition of Timing Specification Parameters

#### APPLICATIONS INFORMATION

#### **Level Translator Architecture**

The NLSX4378A auto sense translator provides bi–directional voltage level shifting to transfer data in multiple supply voltage systems. This device has two supply voltages,  $V_L$  and  $V_{CC}$ , which set the logic levels on the input and output sides of the translator. When used to transfer data from the  $V_L$  to the  $V_{CC}$  ports, input signals referenced to the  $V_L$  supply are translated to output signals with a logic level matched to  $V_{CC}$ . In a similar manner, the  $V_{CC}$  to  $V_L$  translation shifts input signals with a logic level compatible to  $V_{CC}$  to an output signal matched to  $V_L$ .

The NLSX4378A consists of four bi-directional channels that independently determine the direction of the data flow without requiring a directional pin. The one-shot circuits are used to detect the rising input signals. In addition, the one shots decrease the rise time of the output signal for low-to-high transitions.

Each input/output pin has an internal  $10 \text{ k}\Omega$  pull-up resistor. The magnitude of the pull-up resistors can be reduced by connecting external resistors in parallel to the internal  $10 \text{ k}\Omega$  resistors.

#### **Input Driver Requirements**

The rise (t<sub>R</sub>) and fall (t<sub>F</sub>) timing parameters of the open drain outputs depend on the magnitude of the pull-up resistors. In addition, the propagation times (t<sub>PD</sub>), skew (t<sub>SKEW</sub>) and maximum data rate depend on the impedance of the device that is connected to the translator. The timing

parameters listed in the data sheet assume that the output impedance of the drivers connected to the translator is less than 50  $\Omega$ .

#### **Enable Input (EN)**

The NLSX4378A has an Enable pin (EN) that provides tri–state operation at the I/O pins. Driving the Enable pin to a low logic level minimizes the power consumption of the device and drives the I/O  $V_{\rm CC}$  and I/O  $V_{\rm L}$  pins to a high impedance state. Normal translation operation occurs when the EN pin is equal to a logic high signal. The EN pin is referenced to the  $V_{\rm L}$  supply and has Overvoltage Tolerant (OVT) protection.

#### **Power Supply Guidelines**

During normal operation, supply voltage  $V_L$  can be greater than, less than or equal to  $V_{CC}$ . The sequencing of the power supplies will not damage the device during the power up operation.

For optimal performance, 0.01  $\mu F$  to 0.1  $\mu F$  decoupling capacitors should be used on the  $V_L$  and  $V_{CC}$  power supply pins. Ceramic capacitors are a good design choice to filter and bypass any noise signals on the voltage lines to the ground plane of the PCB. The noise immunity will be maximized by placing the capacitors as close as possible to the supply and ground pins, along with minimizing the PCB connection traces.

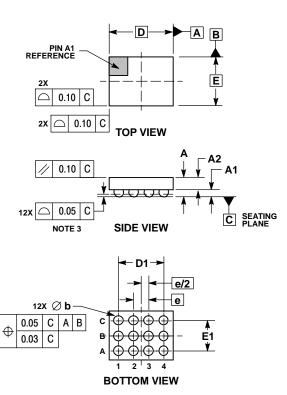
#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NLSX4378ABFCT1G	μΒump12 (Backside Laminate Coating) (Pb–Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

μBump12, 2.02x1.54, 0.5P CASE 499AU **ISSUE O** 



#### NOTES:

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  COPLANARITY APPLIES TO SPHERICAL
  CROWNS OF SOLDER BALLS.

	MILLIMETERS					
DIM	MIN	MAX				
Α		0.66				
A1	0.21	0.27				
A2	0.33	0.39				
b	0.29	0.34				
D	2.02	BSC				
D1	1.50	BSC				
Е	1.54	BSC				
E1	1.00	BSC				
е	0.50	BSC				

ON Semiconductor and 🕠 are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor and it are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or input to the products and distributors and blod distributors and blod distributors and sagainst all claims costs. in a foreign jurisdiction of any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that ON Semiconductor was negligent regarding the design or manufacture of the part. ON Semiconductor is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support:

Phone: 421 33 790 2910

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative